Special Issue

High Precision Measurements of Fundamental Constants

Guest Editor:

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Message from the Guest Editor

Dear Colleagues,

Precision experiments with atomic systems provide an important avenue for testing our understanding of the laws of nature. Along with theoretical advances, they enable significant improvement in the determination of fundamental physical constants. In keeping with the advancing precision of measurements, certain physical constants will be selected to assume a far-reaching role in metrology. In 2018, the International System of Units (SI) is scheduled to undergo a framework revision wherein a set of seven exactly-defined fundamental constants would form the new basis for defining the SI units. This Special Issue highlights recent works, innovations and challenges in high precision measurements of fundamental constants.

Dr. Joseph N. Tan
Guest Editor

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